

ON Semiconductor®

FQA6N90C-F109

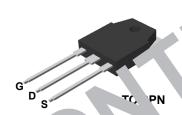
N-Channel QFET $^{\circledR}$ MOSFET 900 V, 6 A, 2.3 Ω

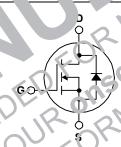
Features

- 6 A, 900 V, $R_{DS(on)}$ = 2.3 Ω (Max.) @ V_{GS} = 10 V, I_D = 3 A
- Low Gate Charge (Typ. 30 nC)
- Low Crss (Typ. 11 pF)
- 100% Avalanche Tested
- · RoHS Compliant

Description

This N-Channel enhancement mode power MOSFET is produced using ON Semiconductor's proprietary planar stripe and DMOS technology. The anneed MOSFET technology has been especially to red to educe on-state resistance, and to provide subject of subject of the subje





Absolute Maximum Rat 1gs Tc 25°C less otherwise in the J

Symbol	P ametei	FQA6N90C-F109	Unit
V _{DSS}	Drain-S vrce Vol' je	900	V
I _D	Drain Cu. + - Contin. oub (T _C = 25°C)	6.0	Α
	- Continuous (T _C = 100°C)	3.87	Α
I _{D'}	reint - Pulsed (Note 1)	24.0	Α
rss	Gate-Source Voltage	± 30	V
E,	Sir glo Pulsed Avalunche Energy (Note 2)	650	mJ
I _{AR}	Av llanche Curreni (Note 1)	6.0	Α
E _{AR}	Repetitiv - Avalanche Energy (Note 1)	19.8	mJ
dv/a:	Peak Diode Cero very dv/dt (Note 3)	4.0	V/ns
₽ _D	Power Discipation (T _C = 25°C)	198	W
	- Derate above 25°C	1.59	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	FQA6N90C-F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.63	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max	40	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA6N90C-F109	FQA6N90C	TO-3PN	Tube	N/A	N/A	30 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics			I.		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	900			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		1.07		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 900 V, V _{GS} = 0 V	-		10	μА
		V _{DS} = 720 V, T _C = 125°C			100	μ Δ .
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	eristics		V		11	-1
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 2$, uA	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, 3.0 ,	-02	1.93	2.3	Ω
9 _{FS}	Forward Transconductance	V _{De} = 5 /, I _D 3.0.	0-7	5.5		S
Dynamic Characteristics						
C _{iss}	Input Capacitance	V_{DS} 25 V, V_{S} = 0 V,	109	1360	1770	pF
C _{oss}	Output Capacitance	f = 1. 1Hz	O = ,	110	145	pF
C _{rss}	Reverse Transfer Capacitance	I CALLE	-52	11	15	pF
Switching C	Characteristics	100-5				
t _{d(on)}	Turn-On Delay Time	'' _{O,O} = 450 V ' _D = 6 0A,		35	80	ns
t _r	Turn-On Rise Ime	R3 = 25 \O	-	90	190	ns
t _{d(off)}	Turn ela, ime	(Note 4)		55	120	ns
t _f	Tu of ime	(11016-4)		60	130	ns
Q _p	tal Cate Clarge	$V_{OS} = 720 \text{ V}, I_D = 6.0\text{A},$		30	40	nC
s	Ga. Source Charge	$V_{G3} = 10 \text{ V}$	-	9.0		nC
Q ₉	Gate-Dr₅in Charge	(Note 4)	-	12		nC
Drain Jourg	ce Diogo Characteristics and Maximum Ratings					*
Is	Maximum Continuous Drain -Source Diode For	rward Current			6.0	Α
I _{SM}	Maximum Pulsed Lirain-Source Diode Forward	d Current	-		24	Α
Ver	Drain-Source Diodo Forward Voltage	V _{GS} = 0 V, I _S = 6.0 A			1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 6.0 A,		630		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs		6.9		μС

^{1.} Repetitive rating: pulse-width limited by maximum junction temperature.

^{2.} L = 34 mH, I $_{AS}$ = 6 A, V $_{DD}$ = 50 V, R $_{G}$ = 25 $\Omega,$ starting T $_{J}$ = 25 $^{\circ}C.$

 $^{3.}I_{SD} \le 6$ A, di/dt ≤ 200 A/ μ s, $V_{DD} \le BV_{DSS}$, starting T_J = 25°C.

^{4.} Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

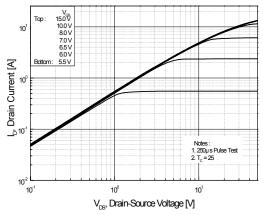


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 2. Transfer Characteristics

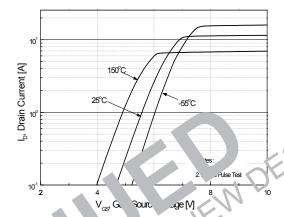


Figure 4. L dy fod Forward Voltage
Va ation vs. Source Current
an emperature

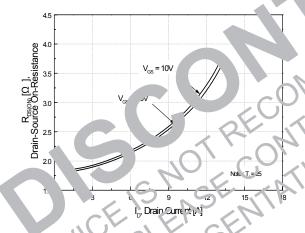
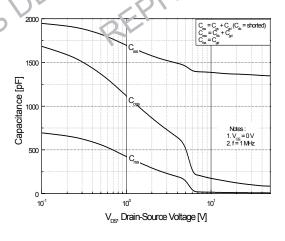


Figure 5. Capacitance Characteristics

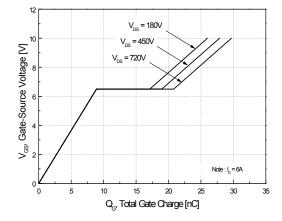


10 1 150 25 Notes:
1. V = 50 V

10 0.2 0.4 0.6 0.8 1.0 1.2 1.4

V_{Sry} Source-Drain voltage [V]

Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

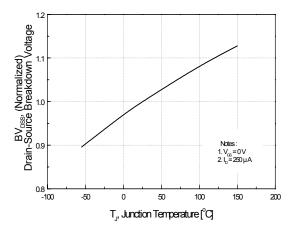
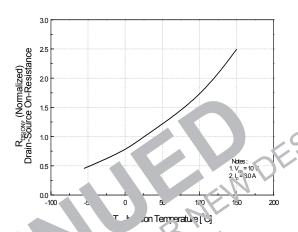


Figure 9. Maximum Safe Operating Area

Figure 8. On-Resistance Variation vs. Temperature



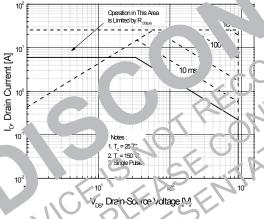
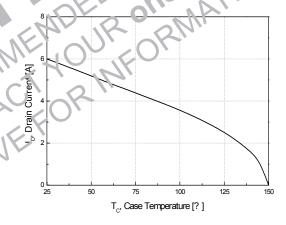
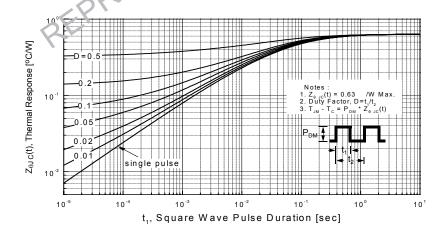


Figure 11. Transient Therma! Response Curve





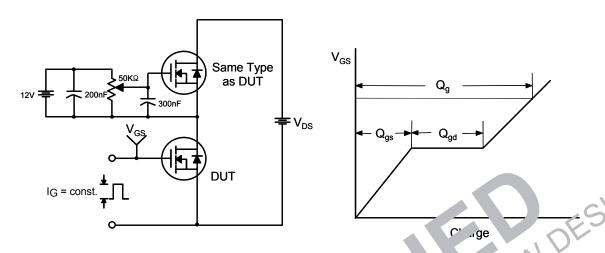


Figure 12. Gate Charge Test Circuit & Vave. m

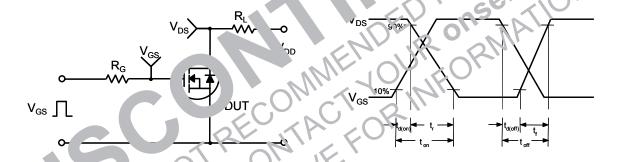


Figure 13. Resistive Switching Test Circuit & Waveforms

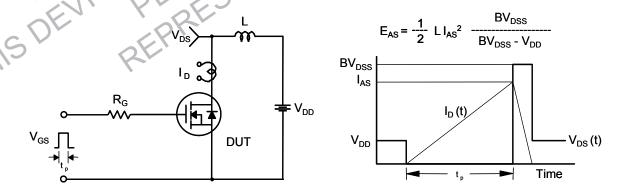


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

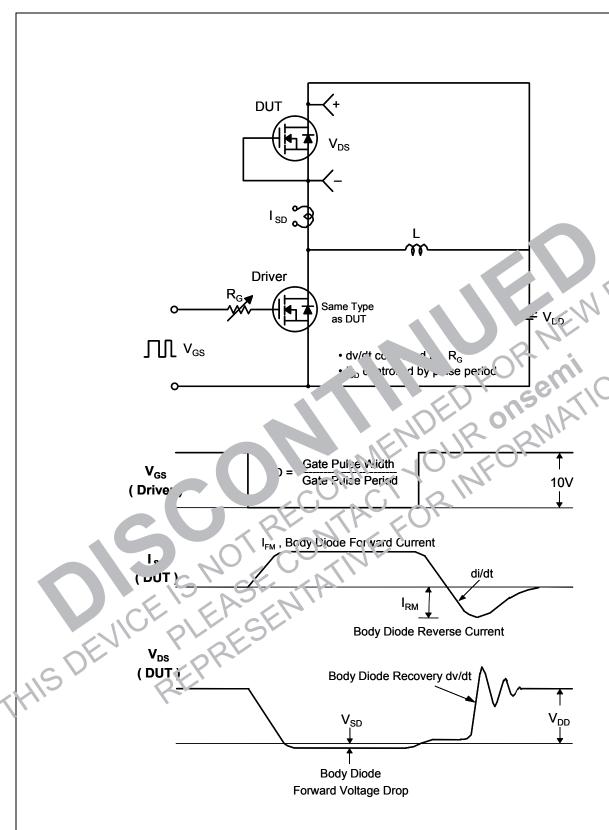


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Mechanical Dimensions 5.00 4.60 13.80 13.40 Ø 3.30 3.10 1.65 16.20 5.20 1.45 15.40 4.80 (R0.50 16.96 20.10 18.90 16.56 19.70 18.50 3 3.70 (1.85)3.30 2.20 1.80 3.20 2.80 1.20 0.80 $\oplus | \emptyset$ 0.55 (M)5.45 NOTES: UNLESS OTHERWISE SPECIFIED THIS PACKAGE CONFORMS TO EIAJ SC-65 PACKAGING STANDARD. ALL DIMENSIONS ARE IN MILLIMETERS. R0.5 DIMENSION AND TOLERANCING PER ASME14.5-2009 DIMENSIONS ARE EXCLUSSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSSIONS. E) DRAWING FILE NAME: TO3PN03AREV1.

Figure 16. TO3PN, 3-Lead, Plastic, EIAJ SC-65

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